



**international**

**reliability physics symposium**

**NEWS RELEASE**

**2004 INTERNATIONAL RELIABILITY PHYSICS SYMPOSIUM  
(IRPS) 42nd ANNUAL EVENT UNDERWAY IN PHOENIX**

*Record number of papers highlight this year's conference*

PHOENIX, ARIZ. – April 28, 2004 – The 42<sup>nd</sup> annual IEEE International Reliability Physics Symposium (IRPS) opened Sunday, April 25<sup>th</sup> at the Hyatt Regency Phoenix at Civic Plaza, Phoenix, Ariz., with increased attendance and the largest numbers of papers submitted and accepted in IRPS history. Over two dozen exhibitors are on hand to display the latest in chip and semiconductor manufacturing equipment to the approximately 600 engineers and research scientists attending. The symposium will run through April 29, 2004.

"IRPS this year continues to be an essential conference to the semiconductor industry with 222 papers submitted and 103 platform papers and 60 posters accepted," said Tim Rost, the 2004 IRPS vice general chairman. "In addition to a full slate of tutorials and vendor demos to highlight new capabilities we are also pleased to have had Hans Stork, Chief Technology Officer (CTO) at Texas Instruments provide the keynote address on the reliability challenges of SoC. For professionals interested in semiconductor reliability, the 2004 IRPS will be time well spent."

Dr. Stork spoke on "Reliability Challenges of sub 100nm-CMOS SoC" on Tuesday, April 27, at the Hyatt Regency Phoenix. Copies of the keynote address are available on CD-ROM to the media by contacting [jack.urso@mastopr.com](mailto:jack.urso@mastopr.com).

Also on April 27, and in keeping with tradition, special recognition for papers from the 2003 IRPS were awarded in a special ceremony. Topics and authors were recognized in two categories. They included:

**Outstanding Paper:** Growth and Scaling of Oxide Construction after Breakdown was presented to Barry P. Linder, James H. Stathis, David J. Frank (IBM, Yorktown Heights, NY), Salvatore Lombardo (CNR-IMETEM, Catania, Italy), and Alex Vayshenker (IBM, Hopewell Jct., NY).

**Best Paper:** A Phenomenological Theory of Correlated Multiple Soft-Breakdown Events in Ultra-thin Gate Dielectrics was presented to Muhammad A. Alam (Agere Systems, Berkeley Heights, NJ) and R. Kent Smith.

### **About IRPS**

For over 40 years, IRPS has been one of the leading meetings for engineers in the area of electronic component reliability. IRPS promotes the comprehension of reliability and performance of integrated circuits and microelectronic assemblies through an improved understanding of failure mechanisms in the user's environment. Originally started in the early 1960's by the military and aerospace community, IRPS is now sponsored by IEEE Reliability Society and IEEE Electron Devices Society. All accepted IRPS papers will appear in the symposium proceedings publication, as well as on the Virtual IRPS DVD-ROM, which is available now for the previous 2003 IRPS.

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For further information, please visit the IRPS web site at [www.irps.org](http://www.irps.org) or contact:

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